

08-09-02

AF/2800

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Ono et al.	Examiner:	J. Mitchell
Serial No.:	09/842487	Group Art Unit:	2822
Filed:	April 25, 2001	Docket:	10873.0447USD1
Confirmation No.:	7930	Notice of Allow.	N/A
		Date:	
Due Date:	August 7, 2002		
Title:	EDGE TESTING ELECTRODE FOR A SEMICONDUCTOR DEVICE		

## CERTIFICATE UNDER 37 CFR 1.10:

"Express Mail" mailing label number: EV143559713US  
Date of Deposit: August 7, 2002

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By: 

Name: John Junkers

Box AF  
Commissioner for Patents  
Washington, D.C. 20231

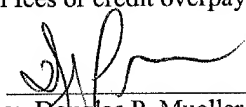
Sir:

We are transmitting herewith the attached:

- ☒ Return postcard
- ☒ Transmittal Sheet in duplicate containing Certificate of Mailing
- ☒ Amendment Including Version With Markings To Show Changes Made

Please consider this a PETITION FOR EXTENSION OF TIME for a sufficient number of months to enter these papers or any future reply, if appropriate. Please charge any additional fees or credit overpayment to Deposit Account No. 13-2725. A duplicate of this sheet is enclosed.

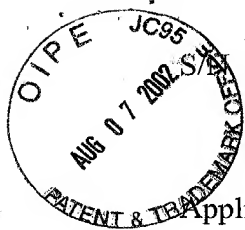
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By:   
Name: Douglas P. Mueller  
Reg. No.: 30,300  
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09/842,487

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	ONO ET AL	Examiner:	J. MITCHELL
Serial No.:	09/842,487	Group Art Unit:	2822
Filed:	APRIL 25, 2001	Docket No.:	10873.447USD1
Title:	EDGE TESTING ELECTRODE FOR A SEMICONDUCTOR DEVICE (PREVIOUSLY: "SEMICONDUCTOR DEVICE")		

CERTIFICATE UNDER 37 CFR 1.10:

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By: 

Name: John Junkers

AMENDMENT AND RESPONSE

BOX AF  
Commissioner for Patents  
Washington, D.C. 20231

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Dear Sir:

In response to the final Office Action mailed May 7, 2002, Applicants provide the following amendments and remarks.

In the Specification

Please amend the title to read as follows:

EDGE TESTING ELECTRODE FOR A SEMICONDUCTOR DEVICE

In the Claims

Please cancel claim 24 without prejudice or disclaimer to the subject matter.

Please amend claim 22 to read as follows.

22. (twice amended) A semiconductor device manufactured by a wire bonding method using a metal wire, comprising a dedicated inspection region adapted to be contacted by a probe needle for inspection brought into contact therewith, and a region in which a metal ball formed at a tip of said metal wire by electric discharge is bonded to a terminal electrode formed on the semiconductor device, wherein a shape of the terminal electrode is rectangular, the shape having a portion protruded from a square that surrounds the region wherein the metal ball is bonded to the terminal electrode, the protruded portion being the dedicated inspection region adapted to be contacted by the probe needle.

